



SHEET 1 OF 1

INFORMATION DISCLOSURE
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APPLICANT
Yutaka HIROSE, et al.

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TJ		JP 11-54788	02/26/1999	TOSHIBA CORP.		JAPAN (w/English Abstract)	
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OTHER ART (including Author, Title, Date, Particular Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
TJ		HASHIZUME, T., et al. "Characterization of GaN and AlGaN Surfaces and Their Insulated Gate Structures." The Institute of Electronics, Information and Communication Engineers. Technical Report of IEICE., ED2002-87, LQE2002-62 (2002-08). Pp. 57-60, June 14, 2002.
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EXAMINER

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*EXAMINER: Initial if reference considered; whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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